

D-108 In Situ Studies of Nano-Particle Growth in Flames—Invited

Journal Article**Author(s):**

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- 2:30 D-61 **GRAZING-INCIDENT X-RAY DIFFRACTION ANALYSES OF NOVEL MAGNETIC THIN FILMS—Invited**
K. Inaba, Y. Ito, K. Omote, H. Toraya, Rigaku Corporation, Tokyo, Japan
- 3:00 D-12 **ULTRA-FAST SIMULTANEOUS FITTING OF SEVERAL BRAGG REFLECTIONS FROM AIAs/GaAs SUPERLATTICES USING METHOD OF EIGENWAVES**
A. Ulyanekov, R. Eisenhower, I. Feranchuk, H. Guérault, H. Röss, Bruker AXS, Karlsruhe, Germany
- 3:20 **Break**
- 3:50 D-5 **THE DIRECT DETERMINATION OF X-RAY DIFFRACTION DATA FROM SPECIFIC DEPTHS**
A. Broadhurst, K.D. Rogers, D.W. Lane, T.W. Lowe, Cranfield University, Swindon, UK
- 4:10 D-70 **“BaF₂ PROCESS”: PHASE EVOLUTION OF Ba₂YCu₃O_{6+x} FILMS**
W. Wong-Ng, I. Levin, M.D. Vaudin, L.P. Cook, National Institute of Standards & Technology, Gaithersburg, MD
R. Feenstra, Oak Ridge National Laboratory, Oak Ridge, TN
- 4:30 D-89 **IN-SITU HTXRD CHARACTERIZATION FOR THIN FILMS**
E.A. Payzant, S.A. Speakman, Oak Ridge National Laboratory, Oak Ridge, TN

XRD

Wednesday p.m.

Twilight

Session D-1 Small Angle Scattering

Organized by: **N.S. MURTHY**, University of Vermont, Burlington, VT
J.D. LONDONO, DuPont Company, Wilmington, DE

- 2:00 D-108 **IN SITU STUDIES OF NANO-PARTICLE GROWTH IN FLAMES—Invited**
G. Beaucage, N. Agashe, University of Cincinnati, Cincinnati, OH
H.K. Kammler, S.E. Pratsinis, Institute of Process Engineering, ETH Zentrum, Zurich, Switzerland
J. Ilavsky, P. Jemian, UNICAT, Advanced Photon Source, Argonne, IL
T. Narayanan, ID02, European Synchrotron Research Facility, Grenoble, France
D. Londono, Dupont Experimental Station, Wilmington, DE
- 2:30 D-106 **IN-SITU STRUCTURAL STUDIES OF SEMICRYSTALLINE POLYMER BLENDS USING SYNCHROTRON RADIATION—Invited**
P. Thiyagarajan, S. Seifert, Argonne National Laboratory, Argonne, IL
M. Kipper, B. Narasimhan, Iowa State University, Ames, IA
- 3:00 D-91 **LOOKING AT SMALL HOLES: CROSS-VALIDATION OF SAXS- AND BET-POROSIMETRY**
P. Laggner, Austrian Academy of Sciences, Graz, Austria and Hecus X-ray Systems GmbH, Graz, Austria
- 3:20 **Break**
- 3:40 D-101 **FROM LAB TO FAB: THE DEVELOPMENT AND DEPLOYMENT OF NEW METROLOGY TECHNOLOGY FOR THE GLOBAL SEMICONDUCTOR INDUSTRY—Invited**
B. Landes, B. Kern, J. Niu, C. Mohler, J. Hahnfeld, D. Yontz, K. Ender, C. Silvis, R. Strittmatter, L. Moore, T. Stokich, D. King, Dow Chemical Co., Midland, MI
J. Quintana, S. Weigand, Northwestern University, Chicago, IL